Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002

CB Certificate No.: JQAQ0002-001-T

TESTD PARTS

Fixed capacitor, Fixed resistor, Semiconductor Integrated Circuit

ENVIRONMENTAL TEST

IEC 60068-2-1:2007 Cold
IEC 60068-2-2:2007 Dry heat

STRESS TEST

JEITA ED-4701/302A:2020
Environmental and endurance test methods for semiconductor devices
(Stress test I-2)
Test method 305D Charged device model electrostatic discharge (CDM/ESD)

Japan Quality Assurance Organization (JQA)
4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan

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MEASUREMENT RANGE

Passive component

Type / Part name	Measurable property value	Measuring range
Fixed capacitor	(1)Voltage endurance (DC)	: AC,DC 0 ~ 5kV
	(2)Insulation resistance	: 5 ×10^{5} Ω ~ 10^{14}Ω
	(3)leakage current	: 1×10^{-3} ~ 10 A^{-11}
	(4)Capacitance	: 18pF ~ 1F *
	(5)Dielectric loss tangent(D factor)	: 10^{*} min
	(6)Impedanc	: 1Ω ~ 10^{*}MΩ
	Attention : * The mark varies according to measurement frequency.	
Fixed resistor	(1)Resistance value	:1 Ω ~ 100MΩ
	(2)Insulation resistance	: 5 ×10^{5} Ω ~ 2×0^{14}Ω
	(3)Voltage endurance	: AC,DC 0 ~ 5kV
CMOS IC	(1)The high-level output voltage	:±30V
	(2)The low-level output voltage	:±30V
	(3)The high-level input voltage	:±20V
	(4)Low-level input electric current	:±20V
	(5)High-level output electric current	:±300mA
	(6)Low-level output electric current	:±300mA
	(7)Static consumption electric current	:±300mA
	(8)Input current	:±300mA

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